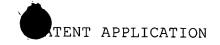
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Attorney Docke No. 015113.0001



ABSTRACT OF THE DISCLOSURE

A system for inspecting components is provided. The system includes a CMOS imaging system generating image data, such as pixel data from a pixel array. An image analysis system is connected to the CMOS imaging system, the image analysis system receiving the image data and generating image analysis data. The CMOS imaging system generates the image data at a rate that allows the CMOS imaging device to be used for inspecting components.